

# Bibliography

## SOURCES OF ADDITIONAL INFORMATION

The published references listed here have appeared in the form of books, manuals, brochures, or articles in archival publications and the trade press. Individual items have been selected because of their general or specific interest—or because of an excellent collection of further references.

Today, articles that mention converters and conversion, in relation to design, testing, system applications, new-product news, etc., are appearing in numbers that grow by leaps and bounds. It is impossible (and might in any case be undesirable) to keep track of them all. In these few pages, no pretense is made as to thoroughness; our goal is to provide a few basic sources that will supplement in greater depth the material presented here.

It is still true that much of the most-advanced, relevant, timely, and useful published material available in this rapidly growing and changing field is published by manufacturers of converters—and of systems that use them—in the course of the ordinary business of trying to sell their products. As noted earlier, Databooks, Application Guides, Application Notes, and Technical Data sheets are available from leading manufacturers in this field—generally free or at nominal cost.\* Such publications are loaded with valuable information that is generally current and useful, particularly in terms of specification definitions and practical application techniques.

Magazines like *Electronic Design*, *EDN*, *Electronic Products*, *Electronic Engineering Times*, and *Computer Design* are good sources of product news and its interpretation, as well as application ideas. In general, their reporters and editors have good technical

\*Publications of Analog Devices, Inc., and reprints that are available as of the initial date of publication of this book are identified by an asterisk (\*); they can be obtained from Analog Devices, Inc., P.O. Box 796, Norwood, Massachusetts 02062. If a given publication is not free, the 1985 unit price (postpaid) in U.S. dollars is included in the listing. Publications not identified by (\*) are *not* available from Analog Devices.

backgrounds, articles are competently written, data and specifications have accuracy as a goal, and readers are provided with various means (such as “bingo” cards, manufacturer’s addresses and telephone numbers, and “hot lines”) to get further information on matters that interest them. However, a cautionary word is in order: products have been known to be introduced in the press (by manufacturers in many fields) long before becoming available for purchase in reasonable quantity—and the preliminary specifications, and even pin connections, can differ from those ultimately established; such preemptive publication may aid planning but is of little help to the designer who needs accurate information for current use.

Every designer should ensure that suppliers keep him or her up to date on new products, applications ideas, and techniques. Manufacturers maintain mailing lists for that purpose. A method employed by Analog Devices since 1967 has been the publication of the technical magazine, *Analog Dialogue*—“A forum for the exchange of circuits, systems, and software for real-world signal processing;” it is mailed free to qualified interested persons.

A medium that appears to be potentially one of the most-promising services to designers employing integrated circuits—including converters and other analog ICs—is the interactive Videolog<sup>SM</sup> database, which is accessible to subscribers’ personal computers via the telephone lines. Videolog maintains an indexed catalog of technical product information from major manufacturers; it is—in principal—always current, because its color-graphic information screens are continuously updatable by the manufacturers as new products appear and older products are de-emphasized or obsoleted. Prices are also made available. It is cross-indexed in several ways, allowing searches by device type, by manufacturer, by part number, by parameters, etc.

Despite its great potential usefulness, Videolog requires a personal computer capable of communicating over telephone lines, and the payment of fees for the service and the use of the telephone lines. Although non-interactive and not as up-to-date, such industry catalogs as *ICMaster*, published by Hearst Business Communications, Inc., are easy to obtain and access—and are quite useful.

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